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STA	TEMENT BY	/ A	PPLICANT	First Named Inventor	Benoit NADEAU-DOSTIE		
		_		Group Art Unit			
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Sheet	1	of	2	Attorney Docket Number	LVPAT067US		

	U.S. PATENT DOCUMENTS							
Examiner Initials	Cite No.1	U.S. Patent I	Document Kind Code ² (if known)	Name of Patentee or Applicant	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
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		6,408,401		BHAVSAR et al.	06/18/2002			
					 			
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			Application Number			
INF	ORMATION	DISCLOSURE	Filing Date			
STATEMENT BY APPLICANT			First Named Inventor	Benoit NADEAU-DOSTIE		
		Group Art Unit				
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Sheet	2	of 2	Attorney Docket Number	LVPAT067US		

Examiner Cite Intitudes name of the author (in CAPITAL LETTERS); title of the article (when appropriate); title of the Item (book, magazine, journal, serials, yenposium, catalog, etc.), date, page(s), outhor-issue number(s), publisher. NAKAHARA et al., "Built-In Self-Test for GHz embedded SRAMS Using Flexible Pattern Generator and New Repair Algorithm", 1999 Proceedings of the International Test Conference, October, 1999, p. 301. McCONNELL et al., "Test Repair of Large Embedded DRAMs: Part 1", Proceedings International Test Conference 2001, October 30 - November 01, 2001 Baltimore, Manuland n. 163 SCHOBER, et al., "Memory Built-In Self-Repair", 2001 Proceedings of the International Trade Conference, October 30 - November 01, 2001, p. 995 KWON et al., "Linear Search Algorithm for Repair Analysis with 4 Spare Row/4 Spare Column", Proceedings of the 2nd IEEE Asia-Pacific Conference on ASIC, Cheju Island, Korea, August 28th, 2000, paper 15.1.			OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS						
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